

A Platform For Adaptive Processing In Machine Tool Vibration Monitoring

**Mike Dillon
The Modal Shop, Inc.
June 18, 2002
The 20th Transducer Workshop**



Motivation

- Deployable signal conditioning
- Deployable signal processing
- Local data bandwidth reduction
- Process vibration data to usable information
- Interface dynamic sensors to infrastructure
- Reduce cost of sensor deployment



Motivation

- Add Dynamic Measurements To Industrial Capabilities
- Remove Traditional Barriers
 - Cost
 - Physical Packaging
 - Network Bandwidth
- Ultimately Empower:
 - Machine Health
 - Tool Wear
 - Part and Process Quality



Traditional Architecture

- Transplant FFT Analyzers
 - Technological Overkill
- PC Board DAQ
 - Significant Engineering Up Front
 - Deployment Issues For Multi-channel



Distributed Architecture

- Integral ICP® signal conditioning
- High resolution 24 bit delta-sigma ADC
 - 96 kHz Bandwidth
- IEEE P1451.4 TEDS sensor support
- Isolated digital inputs & outputs
- Network support
- Programmable DSP
- Local non-volatile program and data storage
- Real-time and time of day clocks



Distributed Architecture

- Sealed NEMA 4 Enclosure
- No Ventilation Required
- < 4 Watts @ 24VDC
- Memory: 32 MB DRAM (5 Minutes of Time History @ 5 kHz)
- Bolt On
- Tamper Proof



Adaptive Processing Application

- Single Spindle Transfer Lines
- Detect Significant Change In Process
 - Tool Faults (loose, broken, or missing)
 - Bearing Failures
- Minimal Configuration Effort



Application Development

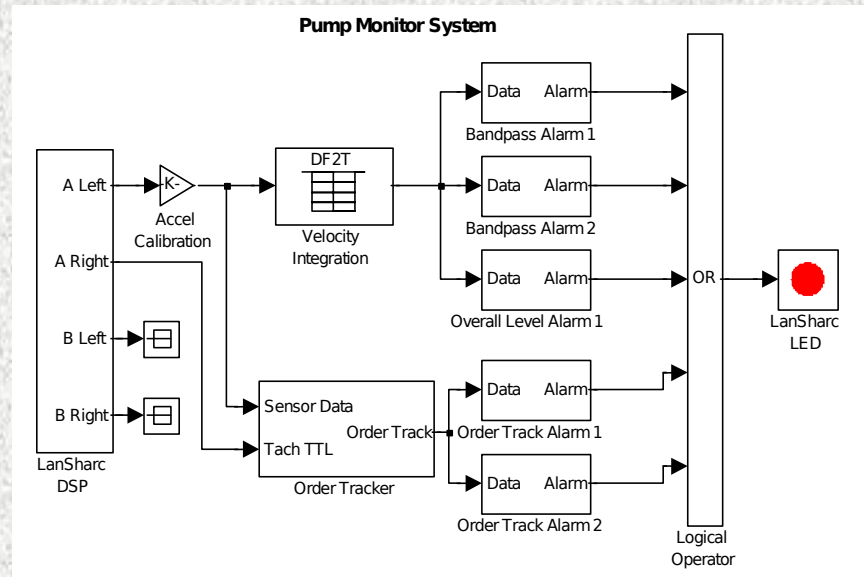
- Prove application using traditional tools
 - FFT analyzer
 - PC based data acquisition
 - Record Actual Plant Data
- Develop Algorithms in Lab Environment
 - Write “C” code
 - Matlab® / Simulink® / Stateflow®



DSPdeveloper + LanSharc

Use Simulink® to program custom applications by drawing block diagrams.

DO THIS!



**NOT
THIS!**

```
#include "pump_mon.h"
#include "pump_mon.ppt"

/* user code (top of source file) */
int cp_val0a[4]; cp_val0a[0] = 0;
segment("DMA_Buffer") volatile int_T Ping0AR[2*(int)256.0];
segment("DMA_Buffer") volatile int_T Pong0AR[2*(int)256.0];

/* chaining pointers for ping/pong buffering */
/*
segment("DMA_Buffer") _tcb rx0a_tcb[2] = {
    {0, 0, 256.0*2, 1, 0}, /* Ch 1 & 2 transmit tcb */
    {1, 0, 256.0*2, 1, 0}}; /* Ch 1 & 2 transmit tcb - set GP reg */

/* model step function */
void pump_mon_step(int_T tid)
{
    /* local block i/o variables */
    real_T rtb_root_Alarm_Level[100];
    real_T rtb_root_Binary_Comparator;
    real_T rtb_s4_Multichannel_IIR_FIR[256];
    real_T rtb_tmpl1[256];

    /* update absolute time */
    if (ssIsSampleHit(pump_mon_rt0, 0, tid)) {
        ssUpdateRealAbsoluteTime(pump_mon_rt0);
    }

    if (ssIsSpecialSampleHit(pump_mon_rt0, 1, 0, tid)) {
        ssUpdateSubtaskTime(pump_mon_rt0, 1);
    }
}

if (ssIsSampleHit(garbage2_rt0, 1, tid)) { /* Sample time: [2.5666666666666666E+000,
0.0] */
    /* Constant Block: <Root>/Alarm Level */
    {
        int_T i1;
        real_T *y0 = &rtb_root_Alarm_Level[0];
        const real_T *p_root_Alarm_Level_Value = &garbage2_Proot_Alarm_Level_Value[0];

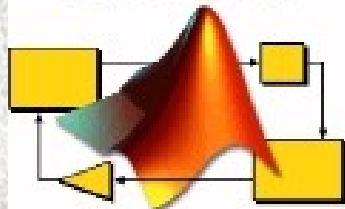
        for (i1=0; i1<100; i1++) {
            y0[i1] = p_root_Alarm_Level_Value[i1];
        }
    }
}
```



Simulink Block Diagram to Application

- SDL's DSPdeveloper enables nonprogrammers to develop custom "smart" applications.
- Develop, simulate and debug in Simulink.
- Compile, link and download bootable, stand-alone applications to flash memory with a single mouse click using DSPdeveloper.

**SIMULINK
Enabled**



MathWorks Partner

DSPdeveloper



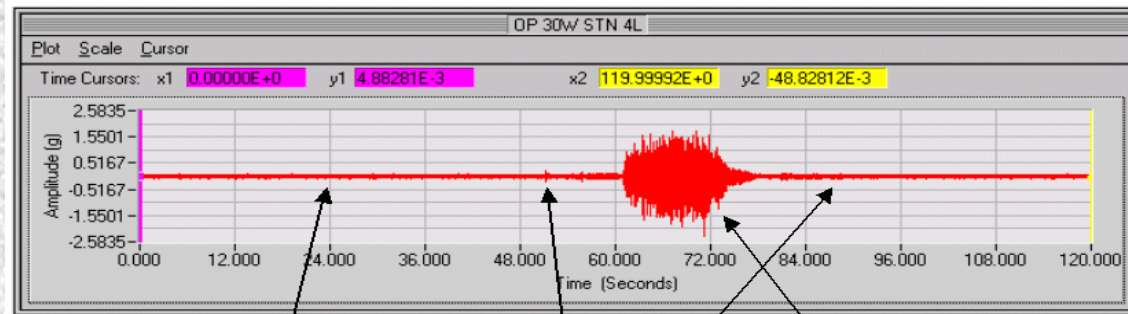
Application Development

- Port Algorithms To LAN Sharc
 - Prove Hardware By Processing Canned Data
- Deploy Pilot Project



Application Development

- Laboratory Algorithm Development
 - Cycle Detection



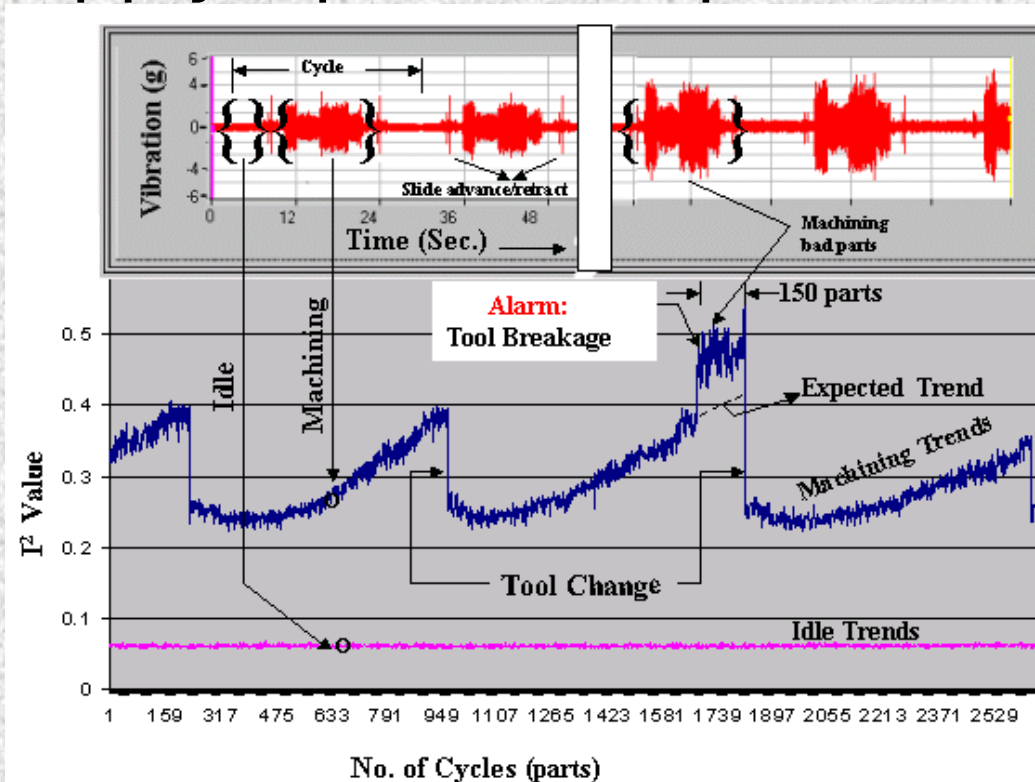
Idle

Transfer Spikes

Machining

Application Development

- Laboratory Algorithm Development
 - Apply Operation Specific Criteria



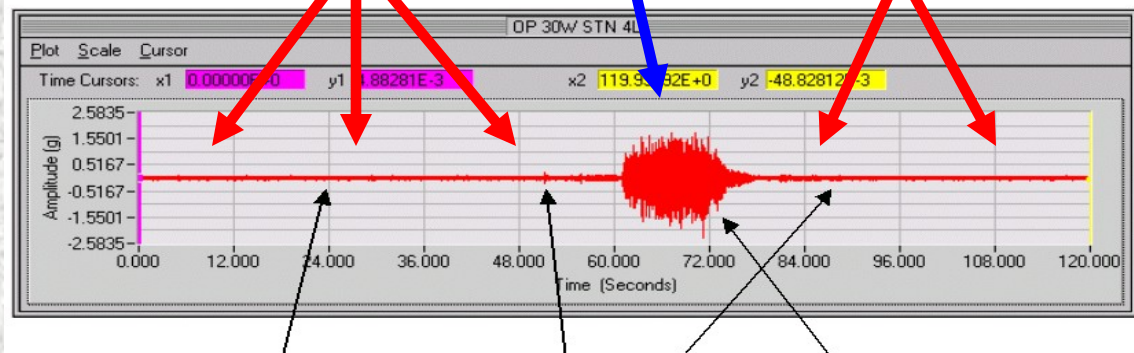
Adaptive Processing

- Alarm Criteria Based On Normalized Distributions
 - Algorithm is 'Seeded' With 20 Machining Cycles of Known 'Good' Quality
 - Statistical Distributions Are Then Found In 'Learn' Mode
 - Finally, 'Test Mode' Applies The Established Criteria



Test Mode

- Evaluate Both On-Cycle and Off-Cycle Parameters



Problems Detected

- Sources of 'Off-Cycle' data Alarms
 - Spindle Bearings
 - Tool Balance
 - Impacts occurring during idle
 - Spindle Preload

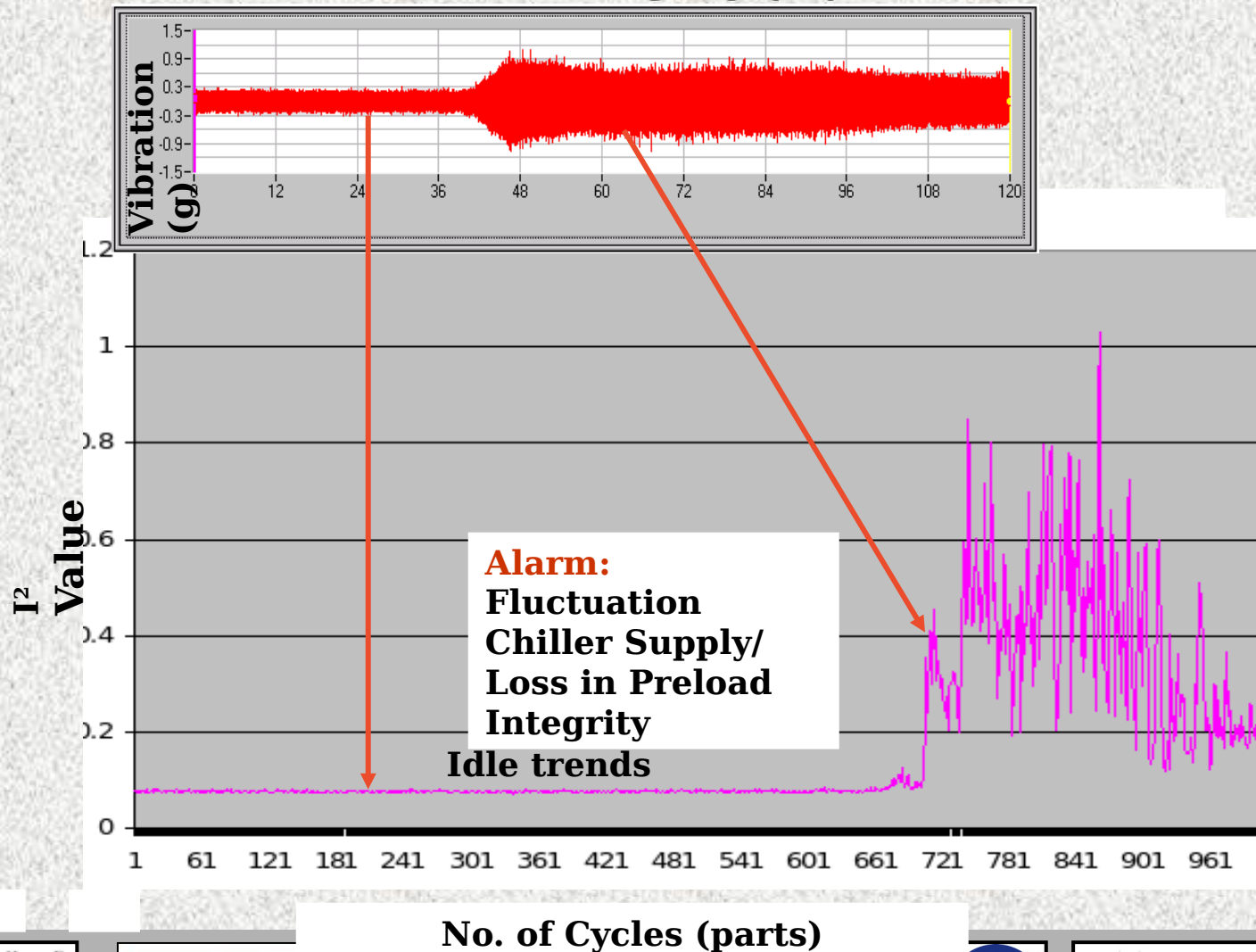


Problems Detected

- Sources of 'On-Cycle' data Alarms
 - Broken or Worn Inserts
 - Workpiece Material Problem
 - Workpiece Clamping Problems



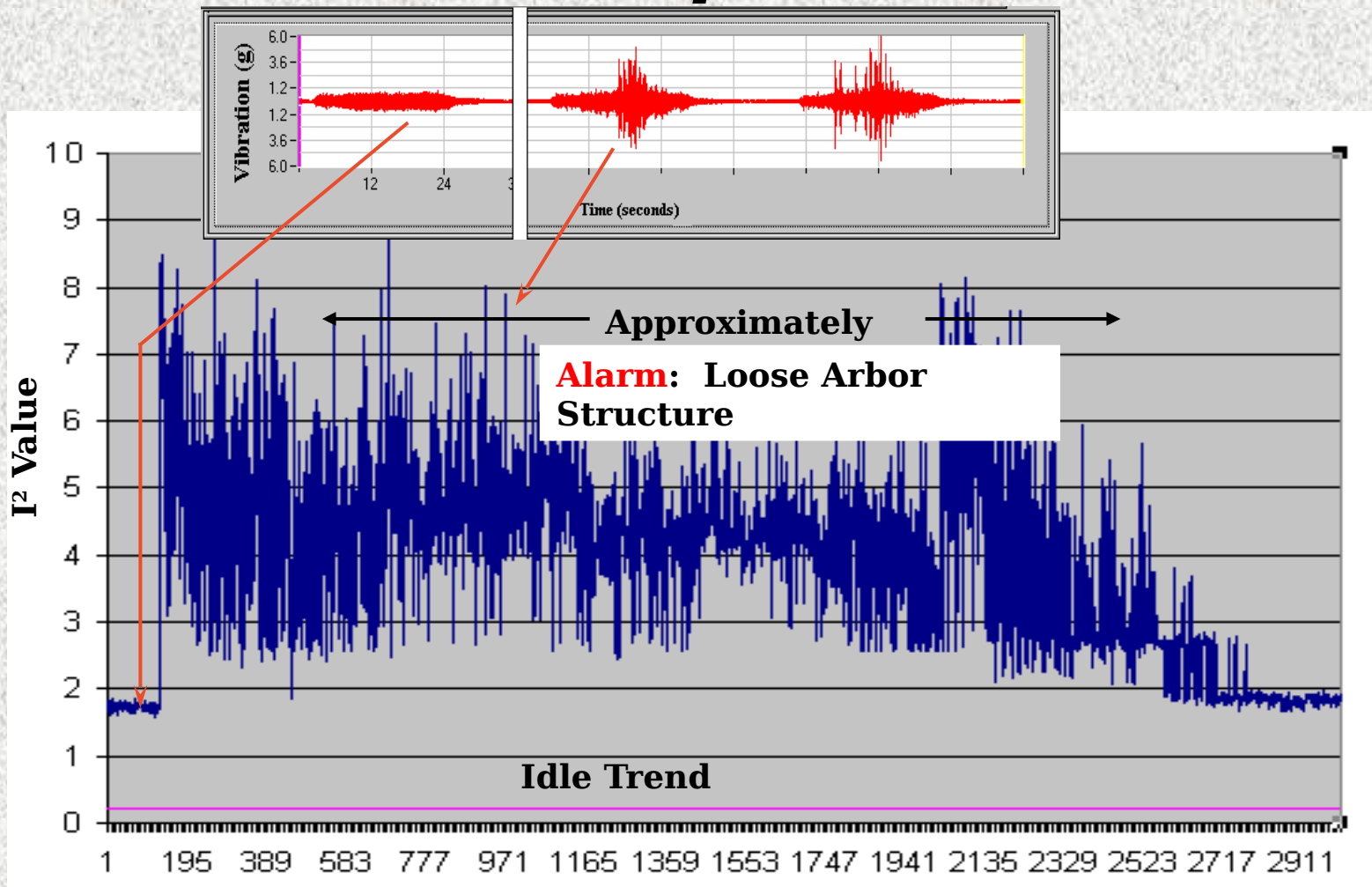
Off-Cycle Alarm - Spindle Preload



No. of Cycles (parts)



On-Cycle - Loose Arbor (Sawing Op)



On-Cycle Detection - Soft Workpiece

